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Docket No.: 049657-0875

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant: Tetsushi TANIZAKI, et al.

RESPONSE UNDER 37 CFR 1.116

EXPEDITED PROCEDURE

Application No.: 09/712,246

Customer No.: 20277

Confirmation No.: 8725

Filed: November 15, 2000

Group Art Unit: 2133

Examiner: M.M. Chaudry

Title: SEMICONDUCTOR MEMORY DEVICE WITH BUILT-IN SELF TEST CIRCUIT  
OPERATING AT HIGH RATE

**AMENDMENT UNDER 37 CFR 1.116**

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

The following Remarks are submitted in response to the Office Action dated January 27, 2005, pursuant to the provisions of 37 C.F.R. § 1.116.

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks** begin on page 4 of this paper.

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